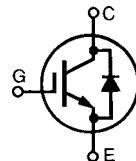


IGBT with Diode ISOPLUS 247™ (Electrically Isolated Backside)

IXSR 35N120BD1

V_{CES}	= 1200 V
I_{C25}	= 70 A
V_{CE(sat)}	= 3.6 V
t_{fi(typ)}	= 180 ns

Short Circuit SOA Capability



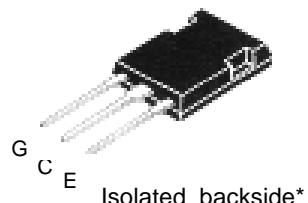
Symbol	Test Conditions	Maximum Ratings		
V _{CES}	T _J = 25°C to 150°C	1200	V	
V _{CGR}	T _J = 25°C to 150°C; R _{GE} = 1 MΩ	1200	V	
V _{GES}	Continuous	±20	V	
V _{GEM}	Transient	±30	V	
I _{C25}	T _C = 25°C	70	A	
I _{C90}	T _C = 90°C	30	A	
I _{CM}	T _C = 25°C, 1 ms	140	A	
SSOA (RBSOA)	V _{GE} = 15 V, T _{VJ} = 125°C, R _G = 22 Ω Clamped inductive load, L = 30 μH	I _{CM} = 90 @ 0.8 V _{CES}	A	
t _{sc} (SCSOA)	V _{GE} = 15 V, V _{CE} = 720 V, T _J = 125°C R _G = 22 Ω, non repetitive	10	μs	
P _c	T _C = 25°C	IGBT Diode	250 150	W W
T _J			-55 ... +150	°C
T _{JM}			150	°C
T _{stg}			-55 ... +150	°C
V _{ISOL}	50/60 Hz, RMS t = 1 min leads-to housing		2500	V~
Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s			300	°C
Weight			5	g

Symbol	Test Conditions	Characteristic Values			
		(T _J = 25°C, unless otherwise specified)	min.	typ.	max.
BV _{CES}	I _C = 3 mA, V _{GE} = 0 V	1200			V
V _{GE(th)}	I _C = 250 μA, V _{CE} = V _{GE}	3		6	V
I _{CES}	V _{CE} = 0.8 • V _{CES} V _{GE} = 0 V	T _J = 25°C T _J = 150°C		1 3	mA mA
I _{GES}	V _{CE} = 0 V, V _{GE} = ±20 V			±100	nA
V _{CE(sat)}	I _C = I _T , V _{GE} = 15 V			3.6	V

① Device must be heatsunk for high temperature measurements to avoid thermal runaway.
IXYS reserves the right to change limits, test conditions and dimensions

ISOPLUS 247™

E 153432



G = Gate, C = Collector,
E = Emitter

* Patent pending

Features

- DCB Isolated mounting tab
- Meets TO-247AD package outline
- High current handling capability
- Latest generation HDMOS™ process
- MOS Gate turn-on
 - drive simplicity

Applications

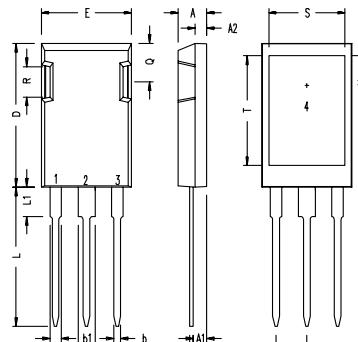
- Uninterruptible power supplies (UPS)
- Switched-mode and resonant-mode power supplies
- AC motor speed control
- DC servo and robot drives
- DC choppers

Advantages

- Easy assembly
- High power density

Symbol	Test Conditions	Characteristic Values			
		(T _J = 25°C, unless otherwise specified)	min.	typ.	max.
g_{fs}	I _C = I _T ; V _{CE} = 10 V, Pulse test, t ≤ 300 μs, duty cycle ≤ 2 %	16	23	S	
C_{iss} C_{oss} C_{rss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	3600 315 75		pF pF pF	
Q_g Q_{ge} Q_{gc}	I _C = I _T , V _{GE} = 15 V, V _{CE} = 0.5 V _{CES}	120 33 49		nC nC nC	
t_{d(on)} t_{ri} t_{d(off)} t_{fi} E_{off}	Inductive load, T_J = 25°C I _C = I _T , V _{GE} = 15 V, L = 100 μH, V _{CE} = 0.8 V _{CES} , R _G = 2.7 Ω Remarks: Switching times may increase for V _{CE} (Clamp) > 0.8 • V _{CES} , higher T _J or increased R _G	36 27 160 180 5		ns ns 300 ns 300 ns 9 mJ	
t_{d(on)} t_{ri} E_{on} t_{d(off)} t_{fi} E_{off}	Inductive load, T_J = 125°C I _C = I _T , V _{GE} = 15 V, L = 100 μH V _{CE} = 0.8 V _{CES} , R _G = 2.7 Ω Remarks: Switching times may increase for V _{CE} (Clamp) > 0.8 • V _{CES} , higher T _J or increased R _G	38 29 6 240 340 9		ns ns mJ ns ns mJ	
R_{thJC} R_{thCK}				0.5 K/W 0.15 K/W	

ISOPLUS 247 OUTLINE



1 Gate, 2 Drain (Collector)
3 Source (Emitter)
4 no connection

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.83	5.21	.190	.205
A ₁	2.29	2.54	.090	.100
A ₂	1.91	2.16	.075	.085
b	1.14	1.40	.045	.055
b ₁	1.91	2.13	.075	.084
b ₂	2.92	3.12	.115	.123
C	0.61	0.80	.024	.031
D	20.80	21.34	.819	.840
E	15.75	16.13	.620	.635
e	5.45	BSC	.215	BSC
L	19.81	20.32	.780	.800
L1	3.81	4.32	.150	.170
Q	5.59	6.20	.220	.244
R	4.32	4.83	.170	.190

Reverse Diode (FRED)

Symbol	Test Conditions	Characteristic Values			
		(T _J = 25°C, unless otherwise specified)	min.	typ.	max.
V_F	I _F = I _T , V _{GE} = 0 V, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %		2.75 1.85		V
I_{RM} t_{rr}	I _F = I _T , V _{GE} = 0 V, -di _F /dt = 100 A/μs V _R = 100 V I _F = 1 A; -di/dt = 200 A/μs; V _R = 30 V	7 40	14.3 ns		A
R_{thJC}			0.83		K/W

Note: 1. I_T = 35A